

Search Notes**Application/Control No.**

10/724,193

Examiner

Toan M. Le

Applicant(s)/Patent under Reexamination

SUNTER, STEPHEN K.

Art Unit

2863

SEARCHED

Class	Subclass	Date	Examiner
702	194	5/5/2005	TL
714	727	5/6/2005	TL
326	21	5/6/2005	TL
324	76.15	5/6/2005	TL
Above	Updated	10/7/2005	TL
Above	Updated	2/9/2006	TL
324	76.77	2/9/2006	TL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Mixed Signal Test Bus	5/6/2005	TL
Boundary Scan, Mixed Signal, Average	5/6/2005	TL
Mixed Signal, Test, Average, Sequence, Difference, IEEE 1149.1, Bus	5/6/2005	TL
Digital Logic Device	5/6/2005	TL
East- See Search History Printout	10/7/2005	TL
IEEE Xplore	10/7/2005	TL
High Speed Signal Average Voltage Logic Voltage Test	2/27/2006	TL
East- See Search History Printout	2/27/2006	TL